

Structure of Sputtered Amorphous Zr-Hf-Si Alloys

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Z. Naturforsch. **54 a**, 699–703 (1999); received November 2, 1999

Amorphous $(\text{Zr,Hf})_{37}\text{Si}_{63}$ alloys were produced by sputtering. Their total structure factors were determined by X-ray diffraction. Using the methods of isomorphous substitution and Reverse Monte Carlo simulation, the partial pair correlation functions were obtained. The results were compared with the partial functions of amorphous $\text{Ti}_{40}\text{Si}_{60}$. In the amorphous alloys under investigation the transition metal – metalloid correlation dominates the short range order.

Key words: Amorphous Zr-Hf-Si; X-ray Diffraction; RMC Model.